

Form Talysurf[®] i-Series

A high resolution instrument range offering automated surface and contour inspection









The Form Talysurf i-Series

A high range high resolution system for contour and surface finish measurement

Ideally suited for automotive, bearings, gears and many other applications

Surface and Contour in One

The Form Talysurf i-Series is a high accuracy instrument range capable of simultaneous surface finish and contour measurement. The system's low noise axes and high resolution gauge ensures measurement integrity with choice of gauge ranges providing versatility for a variety of applications.

Reproducible measurement results

Decades of experience, ultra precision machining expertise and FEA optimized design combine to provide low noise and near flawless mechanical execution of the measuring axes. Further enhancement via the use of traceable standards and exclusive algorithms effectively eliminates instrument influence from the measurement results.



Gauge Range

Up to 5 mm **Resolution** Down to 0.4 nm



Noise Less than 6 nm Rq



Less than 3.3 µm

Pt Less than 0.25 µm



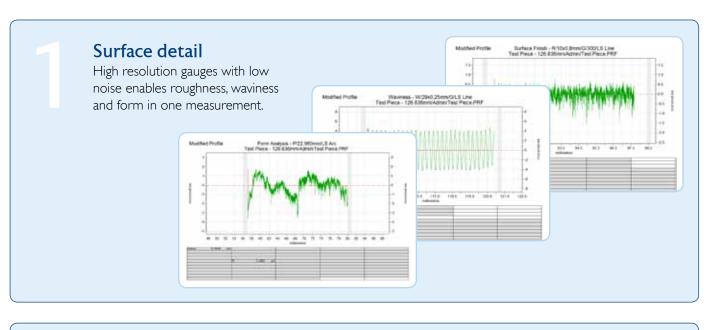
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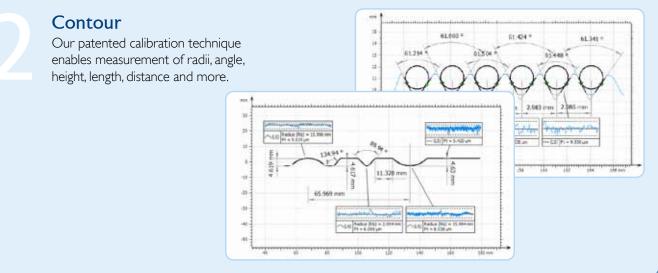
Talysurf i-Series

Temperature compensation ensures consistent system performance

Unparalleled measurement capability

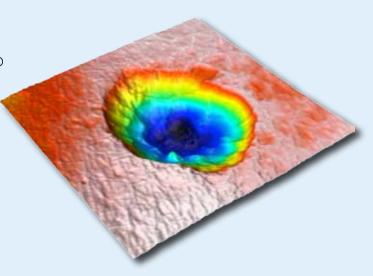
Surface finish, Contour and 3D



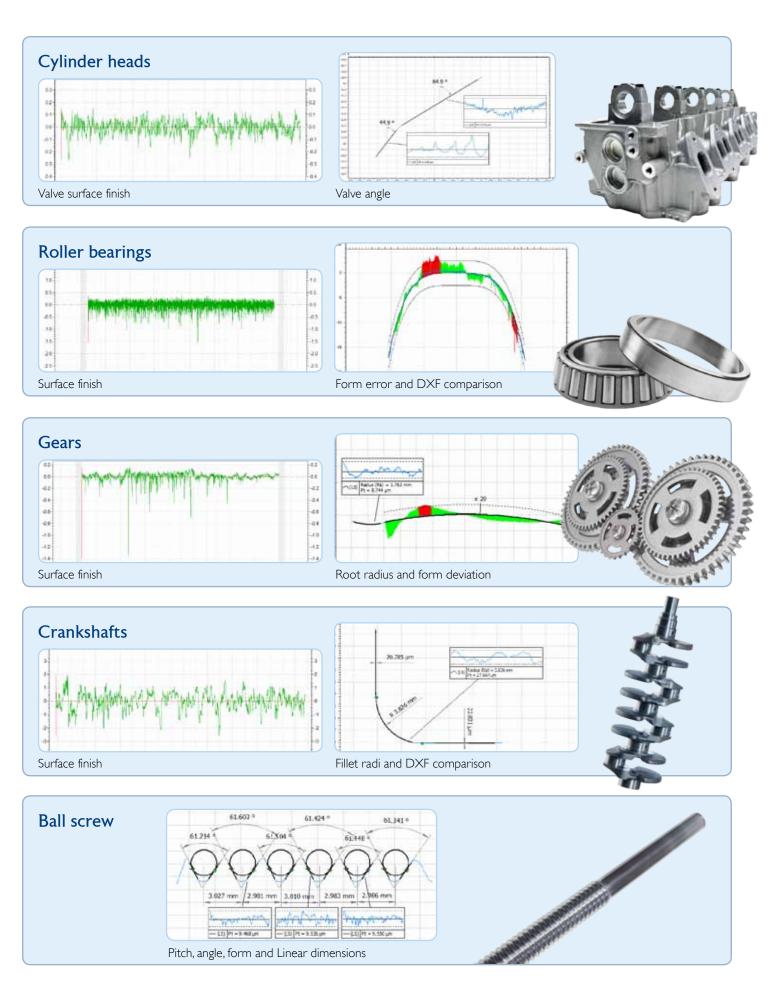


3D

Using an optional motorized Y-stage and Talymap, transform your conventional 2D measurement in to a 3D analysis tool.



Applications



- (1) - 3-463(21 Pitch, angle, form and Linear dimensions



Tailored to suit your application

From screw threads to crankshafts or engine block to valve guides select the configuration that suits your requirements...

Gauge range	1	2	5
60 mm traverse unit	•	•	×
120 mm / 200 mm traverse unit	•	•	•
Contour	•	•	\checkmark
Temperature compensation	✓	\checkmark	\checkmark

✓ Standard ● Option

n 🗴 Not available

Temperature compensation

Standard across all i-Series models, this unique system monitors and feeds back changes in ambient temperature, ensuring consistent system performance and high measurement integrity, regardless of environmental effects.



Ultra surface finish parameters

Powerful software for the analysis of surface finish and form

Form removal and analysis functions

Form error

Deviation from nominal form is calculated with reference to a best fit straight line, best fit circular arc or best fit conic section

Form deviation may also be calculated with reference to a minimum zone straight line (the minimum separation between two parallel lines containing the data set).

Radius

Using a least squares best fit, the radius of concave or convex circular arcs can be automatically calculated from selected data. The option to exclude any unwanted features such as edges is also available

Alternatively, the absolute radius can be set to analyse the actual deviation from a design master. Other calculated parameters include the centre coordinate.

Angle (slope)

Surface tilt can be determined and removed prior to parameter analysis by means of a straight line or minimum zone algorithm. Other calculated values include intercept and pitch

Dimension

The linear relationship of surface features can be assed and compared by means of calculated X & Z coordinate positions.

- Datum slope
- Delta slope
- Pitch (between centres)
- Intercept X / Intercept Z
- Slope

Dual profile

This analysis function enables comparison of one measured profile to another or even to a master profile which has been saved as a template. A 'difference' profile can be displayed at the touch of a button and used for further analyses.

Surface finish parameters

Primary parameters

DFTF, LSLP Ave, LSLP Max, Pa, Pc, PCf, PCI, PCr, Pda*, Pdc*, Pdq*, PHSC*, Pku, PIn, PLo, PIq, Pmr*, Pmr(C)*, Pp, PPc*, Pq, PS, Psk, PSm, Pt, Pv, PVo*, Pz, Pz(JIS)

Roughness parameters

R3y, R3z, Ra, Rc, RCf, RCI, RCr, Rda*, Rdc*, Rdq*, RHSC*, Rku, RIn, RLo, RIq, Rmr*, Rmr(C)*, Rp, Rp1max, Rpc*, Rq, RS, Rsk, RSm, Rt, Rv, Rv1max, RVo*, Rz, Rz(DIN), Rz(JIS), Rz(n)*, Rz1max

Waviness parameters

Wa, Wc, WCf, WCl, WCr, Wda*, Wdc*, Wdq*, WHSC*, Wku, Wln, WLo, Wlq, Wmr*, Wmr(C)*, Wp, WPc*, Wq, WS, Wsk, WSm, Wt, Wv, WVo*, Wz

Rk paramters and Rk curve

A1, A2, APH, AVH, CV, Mr1, Mr2, Rk, Rpk, Rvk, Rvk/Rk

R & W parameters

AR, AW, Pt, R, Rke, Rn, Rpke, Rvke, Rx, Sar, Saw, Sr, Sw, W, Wn, Wte, Wx

Dominant wavelength

WD1c, WD1Sm, WD1t, WD2c, WD2Sm, WD2t, WDSmMax, WDSmMin

Filters and additional features

Filters

Gaussian, Robust Gaussian, Robust Gaussian VDA, Morphological, ISO 2CR, 2CR PC, Rk

Cut-off (Lc)

0.08, 0.25, 0.8, 2.5, 8mm and 25mm

Bandwidth

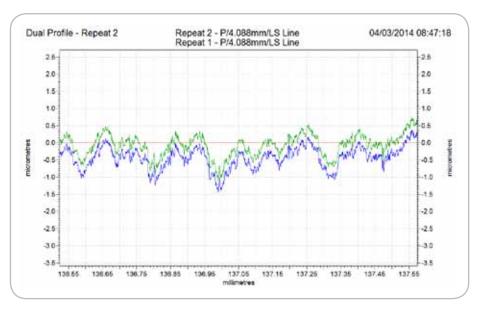
10:1, 30:1, 100:1, 300:1 and 1000:1 or as defined by data spacing(VDA2006)

Qualifiers

All parameters marked with an asterix require user assigned single or multiple qualifiers. For example, material ratio (mr) may be assessed at one or more slice levels within a single measurement.

Note

Where applicable the parameters conform to and are named as per the standards ISO4287-1997, ISO13565-1-2 and ISO 12085.



Dual Profile analysis allows two sets of measurement data to be displayed at once and is ideal for testing system noise and repeatability

Key features in Talymap Contour

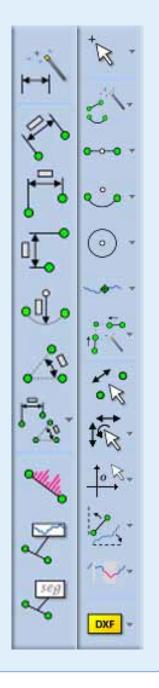
Powerful software for the analysis of length, radius, angle and more...

Desktop publishing

Quick and instant report generation

Ease of use

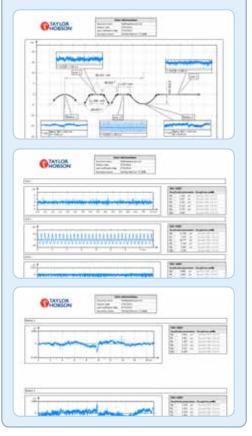
Contour software is easy to use and requires minimal training. Intuitive icon based tools allow the user to define and modify elements and dimensions with the click of a button.

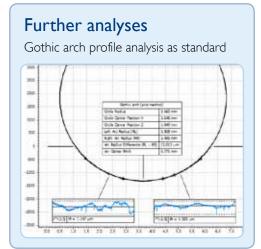


Automation

Reports and analysis routines can be saved as single templates and re-applied to component batches.

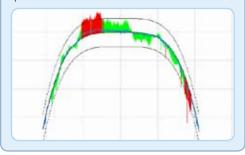
Special software routines allow full automation regardless of part variation or positional set up ensuring repeatable results.





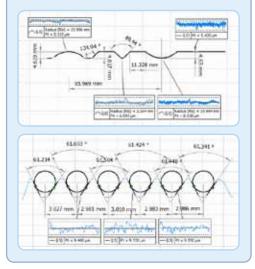
Comparison with CAD models

Load DXF models and automatically fit to the measured profile, results will display deviations, tolerance limits and deviation parameters.



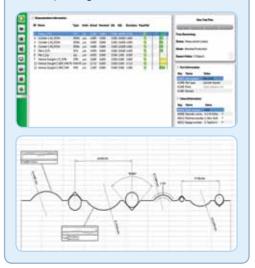
Full dimensional analysis

Linear, Angular, Radial and more



Q-Link Compatible

Take advantage of automatic reporting and exporting in Q-Das or text format.



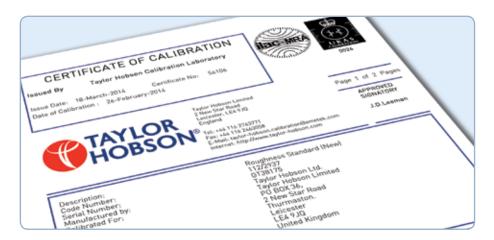
Q-Link Production Interface

A simplified interface designed specifically for production environments

- Q-DAS accredited
- Compatible with all instruments
- Simple operation
- User levels
- Traceable fields
- Simple tolerancing
- Automatic summary reports
- Automatic statistical studies







Traceability Full traceability to international standards

Grating correction

All our traverse units are tested and enhanced using interferometric techniques ensuring accurate dimensional and surface texture measurement in the × direction.

Arcuate correction



Patented ball calibration routine The Form Talysurf systems use a patented ball calibration routine to ensure that both dimensional measurement capability and gauge linearity are dealt with in a single, automated operation.

This fast and simple process uses high-precision spherical calibration artefacts that have been produced to exacting standards and then calibrated for radius and form traceable to international standards.



To ensure the correct gain setting of your instrument, high precision step height standards are available; calibrated uncertainties down to \pm 4nm

Traceability



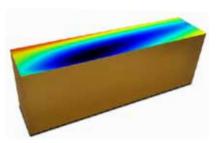
All calibration standards can be provided with traceability to international standards using Taylor Hobson's own UKAS laboratory.



Taylor Hobson can provide glass or metal roughness standards calibrated to an uncertainty of $\pm(2\% + 4 \text{ nm})$ providing measurement confidence and compliance for peak parameters with respect to ISO standards.

Spacing standards are also available to an uncertainty of $\pm 0.6\ \mu\text{m}$

Datum straightness



To ensure the traverse unit conforms to specifications Taylor Hobson can supply Zerodur straightness standards. These standards provide certainty in the traverse direction and are combined with special software routines enhance the measuring axis for correct geometrical form.

Form Talysurf i-Series specification

System performance				Applicable to al	l models		
Calibration Pt ¹				< 0.25 µm (1			
System noise - Rg ²				< 6 nm (0.24	. ,		
Radius measurement unce	ertainty ³	0.1 - 22mm (0.004 - 0.87in) - 1% to 0.015% of nominal 22 - 1000mm (0.87 - 39.4in) - 0.015% to 0.1% of nominal					
Inclination measurement u	Incertainty4	$0.5 \text{ arc minute } (\pm 35^\circ \text{ Maximum Range})$					
	,			Υ.	0,		
Horizontal performance	ce						
Traverse length – X max / min ⁵		60 mm / 0.1 mm (2.4 in /	0.004 in)	120 mm / 0.1 mm (4.7	7 in / 0.004 in)	200 mm / 0.1 mm (7.9 in / 0.004 in)	
Traverse speeds		, , , , , , , , , , , , , , , , , , ,	,	13 mm/s (0.51 ii	<i>,</i>		
Measuring speed ⁶		0.25 mm/s, 0.5 mm/s, 1 mm/s & 2 mm/s (0.01 in/s, 0.02 in/s, 0.04 in/s & 0.08 in/s)					
Minimum data sampling interval in X		0.125 μm (5 μin)					
Straightness accuracy (Pt) ⁷		0.15 µm (5.9 µin)			0.18 µm (7.1 µin)		
X axis indication accuracy ⁸		(1 + 0.02 L) μm					
Vartical parformance							
Vertical performance		1 mm Caura Panza) mm Cause Deser		5 mm Gauge Range	
Nominal measuring range (Z) ⁹ Range 1		1 mm Gauge Range		2 mm Gauge Range		5 mm (0.20 in)	
5		1 mm (0.04 in) 0.2 mm (0.008 in)		2 mm (0.08 in) 1 mm (0.04 in)		2.5 mm (0.10 in)	
Range 2				0.2 mm (0.00		0.5 mm (0.02 in)	
Range 3		0.04 mm (0.002 in)		,	,	0.1 mm (0.004 in)	
Range 4 Resolution (Z) ⁹		Not applicable		0.04 mm (0.002 in)		0.1 11111 (0.004 11)	
Resolution $(Z)^{7}$ Range 1		4 nm (0.16 µin)		8 nm (0.32 µin)		20 nm (0.79 µin)	
Range 2		4 mm (0.16 μm) 0.8 nm (0.03 μm)		4 nm (0.16		10 nm (0.39 μin)	
Range 3		0.16 nm (0.006 µin)		0.8 nm (0.03	. ,	2 nm (0.079 µin)	
Range 4		Not applicable		0.16 nm (0.006 µin)		0.4 nm (0.016 µin)	
Range to resolution				262144 : 1			
Stylus arm length, tip size,	force	60 mm stylus 2 µ	60 mm stylus 2 µm radius conisphere diamond 1mN Eorce 120 mm stylus 2 µm radius			120 mm stylus 2 µm radius conisphere	
Z axis non-linearity		Deseted	diamond, min Force				
(Z = gauge displacement)		Kesolui	Resolution + (0.05 Z[mm])µm (Resolution + (50 Z[inches])µin) after calibration				
Repeatability of Z axis indication ⁹		Flat Surface 0.05um (2.0uin) ¹⁰ Flat Surface 0.1			10um (3.9uin) ¹⁰		
		Curved Surface 0.05um (2.0uin) ¹¹ Curved Surface 0.10um (3.9uin) ¹¹					
Measuring station				Applicable to al	l models		
Motorized tilting of travers	se unit	Optional ±9° from horizontal					
Instrument dimensions		See floor plan					
Instrument weight		223 Kg (450 mm column) (optional 700 mm column 237 Kg)					
Motorized vertical column	1	450 mm (17.7 in) (optional 700 mm (27.6 in))					
Environment			Electric	al (alternating supply, s	single phase wi	th earth, 3-wire)	
Storage temperature	5 °C to 40 °	°C (41 °F to 104 °F)	Supply type Alternating su		Alternating supp	pply, single phase with earth (3-wire system)	
Storage humidity	10 % to 80 9	% relative, non condensing		nent & computer voltage 90 V - 230V			
Operating temperature	18 °C to 22	2 °C (64 °F to 72 °F)		47 Hz to 63 Hz			
Temperature gradient		C / hour (< 3.6 °F / hour)		Supply voltage transients – width EN 61000		.4-4	
Operating humidity		% relative, non condensing		Power consumption 500 VA			
		J	Safety		EN 61010-1		
$ \begin{array}{l} \mbox{Maximum RMS vertical} \\ \mbox{Maximum RMS vertical} \\ \mbox{2.5 } \mu \mbox{m/s} \ (100 \ \mbox{\mu in/s}) \ \mbox{at} < 50 \\ \mbox{5.0 } \mu \mbox{m/s} \ (200 \ \mbox{\mu in/s}) \ \mbox{at} < 50 \\ \end{array} $. ,	EIMI(EN 61000-6-3 EN 61000-6-1		

Notes

3. Assumes a calibration artefact of perfect radius, and use of Gauge Range 1

5. 60 mm traverse unit not available for i5 system

6. For surface texture measurements, speeds of 0.5 mm/s (0.02 in/s) and less are recommended.

 Measured over a glass flat nominally parallel to the traverse datum using a 60mm stylus (1 & i2), 120 mm stylus (5) with a diamond stylus (speed = 2 mm/s, LS Line analysis, Cubic Filter 0.8 mm)

8. Where L is in mm

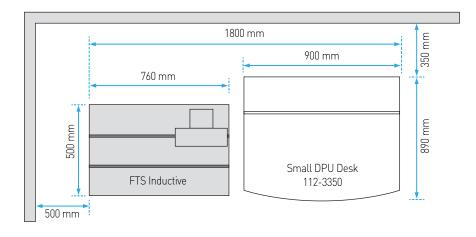
- 9. Using a 60 mm stylus (i1 & i2), 120 mm stylus (i5) with a diamond stylus
- 10. Repeated measurements over a glass flat that is nominally parallel to the datum (full traverse length, primary filter Ls = 0.8 mm)
- 11. Repeated measurements over a 12.5 mm radius standard (i1 & i2), 22.5 mm radius standard (i5) (primary filter LS = 0.25 mm)

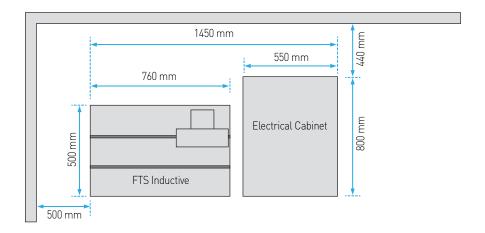
^{1.} LS Arc analysis (primary filter Ls = 0.25 mm)

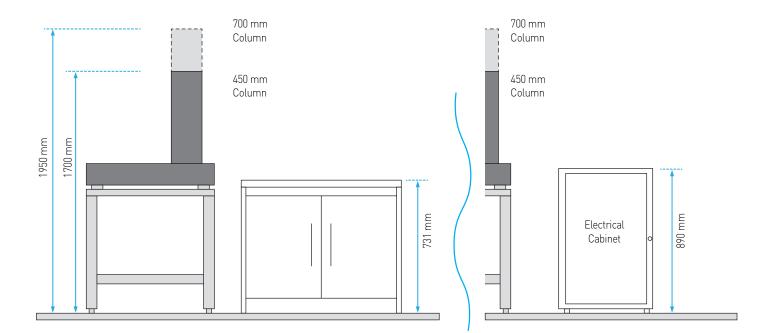
Measured over a glass flat nominally parallel to the traverse datum using a 60 mm stylus (i1 & i2), 120 mm stylus (i5) with a diamond stylus (speed = 0.5 mm/s, Gaussian roughness filter, 0.08 mm cut-off, 30:1 bandwidth) in Range 3

^{4.} Measurements up and down a $\pm 35^{\circ}$ angled slope over 95% of the gauge range using a 60 mm stylus (1 & i2), 120 mm stylus (i5)with a diamond stylus

Form Talysurf i-Series floor plan









Serving a global market

Taylor Hobson is world renowned as a manufacturer of precision measuring instruments used for inspection in research and production facilities. Our equipment performs at nanometric levels of resolution and accuracy.

To complement our precision manufacturing capability we also offer a host of metrology support services to provide our customers with complete solutions to their measuring needs and total confidence in their results.

Contracted services from Taylor Hobson

Sales department

- Email: taylor-hobson.sales@ametek.com Tel: +44 (0)116 246 2034
- Design engineering special purpose, dedicated metrology systems for demanding applications
- · Precision manufacturing contract machining services for high precision applications and industries

Service department

Email: taylor-hobson.service@ametek.com Tel: +44 (0)116 246 2900

· Preventative maintenance protect your metrology investment with an Amecare support agreement

Centre of Excellence department

Email: taylor-hobson.cofe@ametek.com Tel: +44 (0)116 276 3779

- Inspection services measurement of your production parts by skilled technicians using industry leading instruments in accord with ISO standards
- Metrology training practical, hands-on training courses for roundness and surface finish conducted by experienced metrologists
- Operator training on-site instruction will lead to greater proficiency and higher productivity
- UKAS calibration and testing certification for artifacts or instruments in our laboratory or at customer's site





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